

1.	Record Nr.	UNISALENTO991002345869707536
	Autore	Galateria, Luigi
	Titolo	Gli organi collegiali amministrativi / Luigi Galateria
	Pubbl/distr/stampa	Milano : A. Giuffrè, 1975
	Descrizione fisica	v. ; 26 cm.
	Classificazione	AM-IV/D
	Soggetti	Collegi amministrativi Diritto amministrativo
	Lingua di pubblicazione	Italiano
	Formato	Materiale a stampa
	Livello bibliografico	Monografia
	Nota di contenuto	V. 1: La struttura. - 207 p.
2.	Record Nr.	UNISALENTO991002667009707536
	Titolo	The journal of the Walters art Gallery. - 1938-2000
	Pubbl/distr/stampa	Baltimore, 1938-2000
	ISSN	0043-0188
	Altri autori (Enti)	Walters art Gallery
	Lingua di pubblicazione	Inglese
	Formato	Materiale a stampa
	Livello bibliografico	Periodico

3. Record Nr.	UNINA9910299887103321
Autore	Sayil Selahattin
Titolo	Contactless VLSI Measurement and Testing Techniques / / by Selahattin Sayil
Pubbl/distr/stampa	Cham : , : Springer International Publishing : , : Imprint : Springer, , 2018
ISBN	3-319-69673-4
Edizione	[1st ed. 2018.]
Descrizione fisica	1 online resource (V, 93 p. 34 illus., 11 illus. in color.)
Disciplina	621.3815
Soggetti	Electronic circuits Microprocessors Computer architecture Electronics Electronic Circuits and Systems Processor Architectures Electronics and Microelectronics, Instrumentation
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Nota di bibliografia	Includes bibliographical references at the end of each chapters.
Nota di contenuto	1. Conventional Test Methods. -- 2. Testability Design -- 3. Other Techniques Based on the Contacting Probe -- 4. Contactless Testing -- 5. Electron-Beam and Photoemission Probing -- 6. Electro Optic Sampling and Charge Density Probe -- 7. Electric Force Microscope, Capacitive Coupling and Scanning Magneto-Resistive Probe -- 8. Probing Techniques Based on Light Emission from Chip -- 9. All Silicon Optical Technology for Contactless Testing of Integrated Circuits -- 10. Comparison of Contactless Testing Methodologies.
Sommario/riassunto	This book provides readers with a comprehensive overview of the state-of-the-art in optical contactless probing approaches, in order to fill a gap in the literature on VLSI Testing. The author highlights the inherent difficulties encountered with the mechanical probe and testability design approaches for functional and internal fault testing and shows how contactless testing might resolve many of the challenges associated with conventional mechanical wafer testing. The techniques described in this book address the increasing demands for

internal access of the logic state of a node within a chip under test:
Provides a single-source reference on contactless probing approaches for VLSI testing and diagnostic measurement Introduces readers to various optical contactless testing techniques, such as Electro-Optic Probing, Charge Density Probe, and Photo-emissive Probe Discusses the applicability and adaptability of each technique, based on multilayer metallization, wafer level techniques, and invasiveness
Provides a comparison among various contactless testing techniques
Describes a variety of industrial applications of contactless VLSI testing.
